

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/020,717	SILVESTER, KELAN CRAIG	
Examiner		Art Unit		Page 1 of 1
Christopher E. Lee		2112		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,473,789 B1	10-2002	Chen et al.	709/213
	B	US-6,463,142 B1	10-2002	Kilp, David Patrick	379/201.06
	C	US-6,687,778 B2	02-2004	Ito et al.	710/301
	D	US-2002/0002056 A1	01-2002	Kobayashi, Koichi	455/517
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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